

“Nanowire facilitated transfer of sensitive TEM samples in a FIB”. Gorji S, Kashiwar A, Mantha LS, Kruk R, Witte R, Marek P, Hahn H, Kübel C, Scherer T, Ultramicroscopy **219**, 113075 (2020). <http://doi.org/10.1016/J.ULTRAMIC.2020.113075>